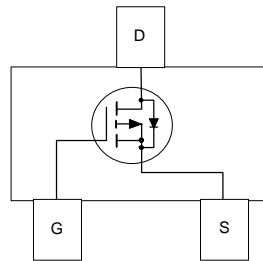
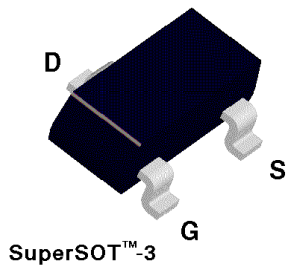


General Description

These P-Channel logic level enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance. These devices are particularly suited for low voltage applications such as notebook computer power management, portable electronics, and other battery powered circuits where fast high-side switching, and low in-line power loss are needed in a very small outline surface mount package.

Features

- -1.1 A, -20V. $R_{DS(ON)} = 0.3\Omega$ @ $V_{GS} = -4.5V$.
- Proprietary package design using copper lead frame for superior thermal and electrical capabilities.
- High density cell design for extremely low $R_{DS(ON)}$.
- Exceptional on-resistance and maximum DC current capability.
- Compact industry standard SOT-23 surface mount package.



Absolute Maximum Ratings

$T_A = 25^\circ\text{C}$ unless otherwise noted

| Symbol | Parameter | NDS356P | Units |
|----------------|--|------------|------------------|
| V_{DSS} | Drain-Source Voltage | -20 | V |
| V_{GSS} | Gate-Source Voltage - Continuous | ± 12 | V |
| I_D | Maximum Drain Current - Continuous (Note 1a) | ± 1.1 | A |
| | - Pulsed | ± 10 | |
| P_D | Maximum Power Dissipation (Note 1a) (Note 1b) | 0.5 | W |
| | | 0.46 | |
| T_J, T_{STG} | Operating and Storage Temperature Range | -55 to 150 | $^\circ\text{C}$ |

THERMAL CHARACTERISTICS

| | | | |
|-----------------|---|-----|--------------------|
| $R_{\theta JA}$ | Thermal Resistance, Junction-to-Ambient (Note 1a) | 250 | $^\circ\text{C/W}$ |
| $R_{\theta JC}$ | Thermal Resistance, Junction-to-Case (Note 1) | 75 | $^\circ\text{C/W}$ |



Electrical Characteristics ($T_A = 25^\circ\text{C}$ unless otherwise noted)

| Symbol | Parameter | Conditions | Min | Typ | Max | Units |
|---|-----------------------------------|--|---|------|------|---------------|
| OFF CHARACTERISTICS | | | | | | |
| BV_{DSS} | Drain-Source Breakdown Voltage | $V_{GS} = 0\text{ V}, I_D = -250\ \mu\text{A}$ | -20 | | | V |
| I_{DSS} | Zero Gate Voltage Drain Current | $V_{DS} = -16\text{ V}, V_{GS} = 0\text{ V}$ | | | -5 | μA |
| | | $T_J = 125^\circ\text{C}$ | | | -20 | μA |
| I_{GSSF} | Gate - Body Leakage, Forward | $V_{GS} = 12\text{ V}, V_{DS} = 0\text{ V}$ | | | 100 | nA |
| I_{GSSR} | Gate - Body Leakage, Reverse | $V_{GS} = -12\text{ V}, V_{DS} = 0\text{ V}$ | | | -100 | nA |
| ON CHARACTERISTICS (Note 2) | | | | | | |
| $V_{GS(th)}$ | Gate Threshold Voltage | $V_{DS} = V_{GS}, I_D = -250\ \mu\text{A}$ | -0.8 | -1.6 | -2.5 | V |
| | | $T_J = 125^\circ\text{C}$ | -0.5 | -1.3 | -2.2 | |
| $R_{DS(on)}$ | Static Drain-Source On-Resistance | $V_{GS} = -4.5\text{ V}, I_D = -1.1\text{ A}$ | | | 0.3 | Ω |
| | | $T_J = 125^\circ\text{C}$ | | | 0.4 | |
| | | $V_{GS} = -10\text{ V}, I_D = -1.3\text{ A}$ | | | 0.21 | |
| $I_{D(on)}$ | On-State Drain Current | $V_{GS} = -4.5\text{ V}, V_{DS} = -5\text{ V}$ | -3 | | | A |
| g_{FS} | Forward Transconductance | $V_{DS} = -5\text{ V}, I_D = -1.1\text{ A}$ | | 1.8 | | S |
| DYNAMIC CHARACTERISTICS | | | | | | |
| C_{iss} | Input Capacitance | $V_{DS} = -10\text{ V}, V_{GS} = 0\text{ V},$ $f = 1.0\text{ MHz}$ | | 180 | | pF |
| C_{oss} | Output Capacitance | | | 255 | | pF |
| C_{rss} | Reverse Transfer Capacitance | | | 60 | | pF |
| SWITCHING CHARACTERISTICS (Note 2) | | | | | | |
| $t_{d(on)}$ | Turn - On Delay Time | $V_{DD} = -10\text{ V}, I_D = -1\text{ A},$ $V_{GS} = -10\text{ V}, R_{GEN} = 50\ \Omega$ | | 7 | 15 | ns |
| t_r | Turn - On Rise Time | | | 17 | 30 | ns |
| $t_{d(off)}$ | Turn - Off Delay Time | | | 56 | 90 | ns |
| t_f | Turn - Off Fall Time | | | 41 | 80 | ns |
| Q_g | Total Gate Charge | | $V_{DS} = -10\text{ V}, I_D = -1.1\text{ A},$ $V_{GS} = -5\text{ V}$ | | 3.5 | 5 |
| Q_{gs} | Gate-Source Charge | | | | 1.5 | nC |
| Q_{gd} | Gate-Drain Charge | | | | 2 | nC |

Electrical Characteristics ($T_A = 25^\circ\text{C}$ unless otherwise noted)

| Symbol | Parameter | Conditions | Min | Typ | Max | Units |
|---|---|---|-----|-------|------|-------|
| DRAIN-SOURCE DIODE CHARACTERISTICS AND MAXIMUM RATINGS | | | | | | |
| I_S | Maximum Continuous Drain-Source Diode Forward Current | | | | -0.6 | A |
| I_{SM} | Maximum Pulsed Drain-Source Diode Forward Current | | | | -4 | A |
| V_{SD} | Drain-Source Diode Forward Voltage | $V_{GS} = 0\text{ V}, I_S = -1.1\text{ A}$ (Note 2) | | -0.85 | -1.2 | V |

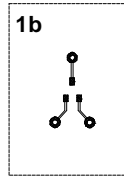
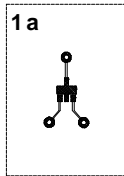
Notes:

- $R_{\theta JA}$ is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.

$$P_D(t) = \frac{T_J - T_A}{R_{\theta J \theta(t)}} = \frac{T_J - T_A}{R_{\theta J} + R_{\theta CA}(t)} = I_D^2(t) \times R_{DS(on)} \theta_{TJ}$$

Typical $R_{\theta JA}$ using the board layouts shown below on 4.5"x5" FR-4 PCB in a still air environment:

- 250°C/W when mounted on a 0.02 in² pad of 2oz copper.
- 270°C/W when mounted on a 0.001 in² pad of 2oz copper.



Scale 1 : 1 on letter size paper

- Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2.0\%$.